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List of Reference Symbols

- 100 Integrated circuit
- 101 Silicon substrate
- 102 Contact-making element
- 103 First field-effect transistor
- 104 Second field-effect transistor
- 105 Gate region
- 106 Gate region
- 200 First layout view of an integrated circuit
- 201 First field-effect transistor
- 202 Second field-effect transistor
- 203 Common gate line
- 203a First gate component
- 203b Second component
- 203c First course direction
- 203d Second course direction
- 203e Third course direction
- 203f Fourth course direction
- 204 Active region
- 204a First course direction
- 204b Second course direction
- 205 Active region
- 205a First course direction
- 205b Second course direction
- 206 First square contact-making element
- 207 Second square contact-making element
- 208 Third square contact-making element
- 300 Second layout view of an integrated circuit
- 301 First rectangular contact-making element
- 301a Third course direction
- 301b Fourth course direction
- 302 Second rectangular contact-making element
- 302a Third course direction
- 302b Fourth course direction
- 303 Third rectangular contact-making element
- 303a Third course direction
- 303b Fourth course direction
- 101 Tithography davice

- 405 Silicon wafer
- 406a Processed chips
- 406b Unprocessed chips
- 406c Chip to be processed
- 407 Aligning optical arrangement
- 408 Reticle
- 409 Lens
- 410 Prealigning optical arrangement
- 411 Laser interferometer
- 412 Mirror area
- 413 xy table
- 414 Objective
- 415 Carrier element
- 440 Flow diagram
- 450 First method step
- 455 Second method step
- 460 Third method step
- 465 Fourth method step
- 470 Fifth method step
- 475 Sixth method step